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TABLE OF CONTENTS

Substrate and Film Structure Impacts on Adhesion Properties Between Lignocellulosic Polymers	1
<i>Elias Estephan, Véronique Aguié-Béghin, Loïc Muraille, Michael Molinari</i>	
Study of Nano-Mechanics of Collagen I Triple-helices by Computerized Processing of AFM Images	7
<i>Arkady Bitler, Emanuel Perugia, Sidney R. Cohen</i>	
Development of a Novel Combined Scanning Electrochemical Microscope (SECM) and Scanning Ion-Conductance Microscope (SICM) Probe for Soft Sample Imaging	13
<i>Andrew J. Pollard, Nilofar Faruqi, Michael Shaw, Charles A. Clifford, Yasufumi Takahashi, Yuri E. Korchev, Neil Ebejer, Julie V. Macpherson, Patrick R. Unwin, Debdulal Roy</i>	
Multi-Frequency Atomic Force Microscopy Combining Amplitude- and Frequency-Modulation Techniques	19
<i>Santiago D. Solares, Gaurav Chawla</i>	
Author Index	